

Search Notes

Application/Control No.

10/757,420

Examiner

EDMUND H. LEE

Applicant(s)/Patent under
Reexamination

YAMAKAWA ET AL.

Art Unit

1732

SEARCHED

Class	Subclass	Date	Examiner
UPDATED		4/30/2007	EHL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
264	162,161	4/30/2007	EHL
83	13	↓	↓

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
UPDATED	4/30/2007	EHL